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(12) **United States Design Patent**
Obana et al.

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(54) **SAMPLE ANALYZER**

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(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (13) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/81**

(58) **Field of Classification Search**
USPC D10/75, 69, 56, 65, 81, 78, 60; D13/118, D13/110, 123; D14/307, 130; D16/130; D24/163, 216, 217; 307/11
CPC G01S 7/4817; G01S 7/4808; G01S 17/08; G01S 17/42; G01C 3/08; G01C 15/008; G01C 1/00; G01C 1/14; H05K 5/00; H05K 5/02; H05K 5/0247; H05K 7/00; H05K 7/20; H05K 7/20136; H05K 7/20154; H05K 7/209; H02M 7/00; H02M 7/003; H02M 2001/009; H02J 7/0042; Y10T 307/367
See application file for complete search history.

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(57) **CLAIM**

We claim the ornamental design for a sample analyzer, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a sample analyzer, showing our new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a top plan view thereof;
FIG. **5** is a bottom plan view thereof;
FIG. **6** is a right side elevational view thereof;
FIG. **7** is a left side elevational view thereof;
FIG. **8** is a perspective view thereof showing an access cover of the sample analyzer in an open state; and,
FIG. **9** is a partial enlarged view taken from rectangle **9** in FIG. **4**.
The dashed broken lines show portions of the sample analyzer that form no part of the claimed design.
The broken line rectangles included in FIGS. **4** and **9** are included for the purpose of illustrating the partial enlarged view and form no part of the claimed design.

1 Claim, 9 Drawing Sheets

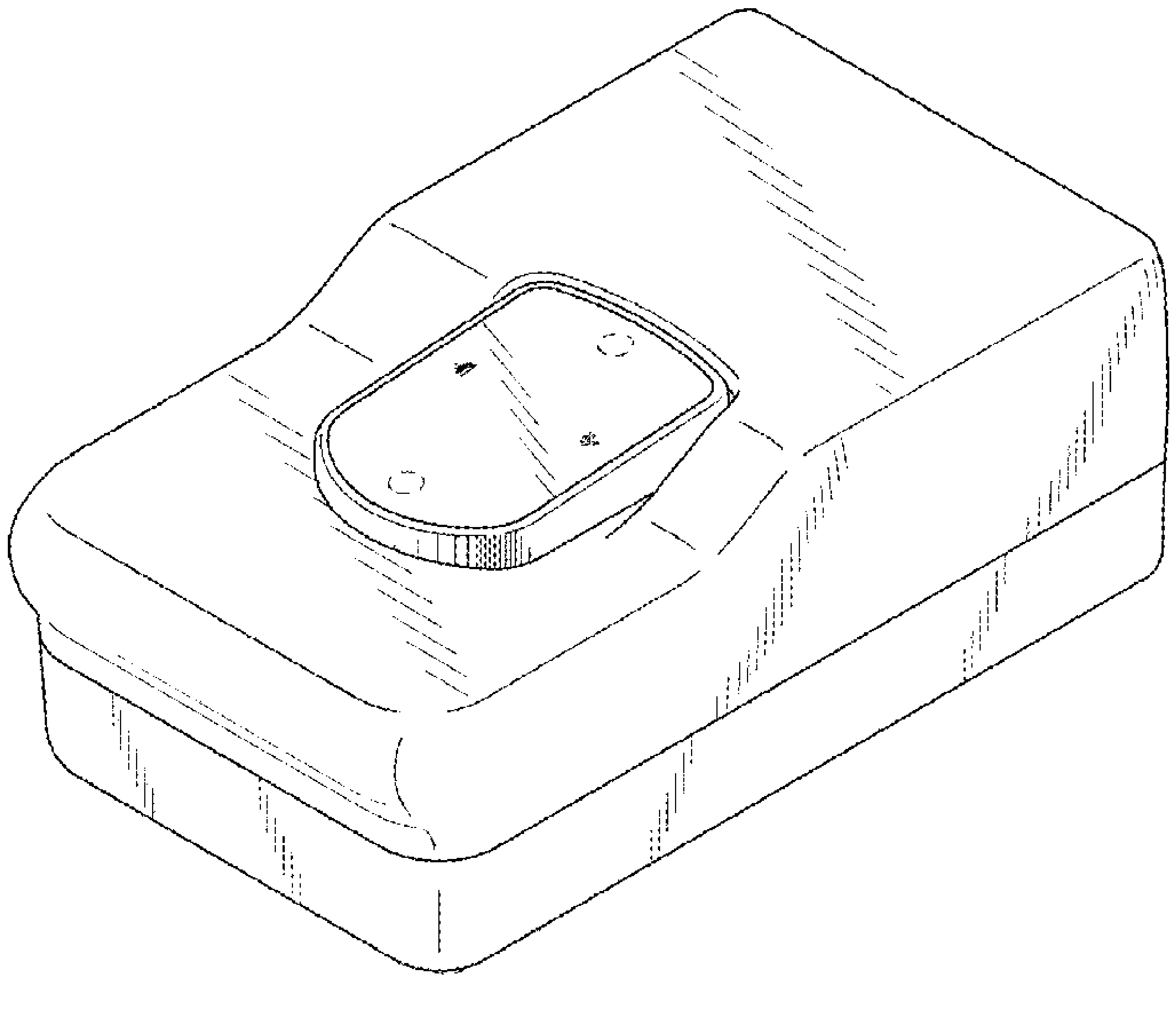

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Fig. 1

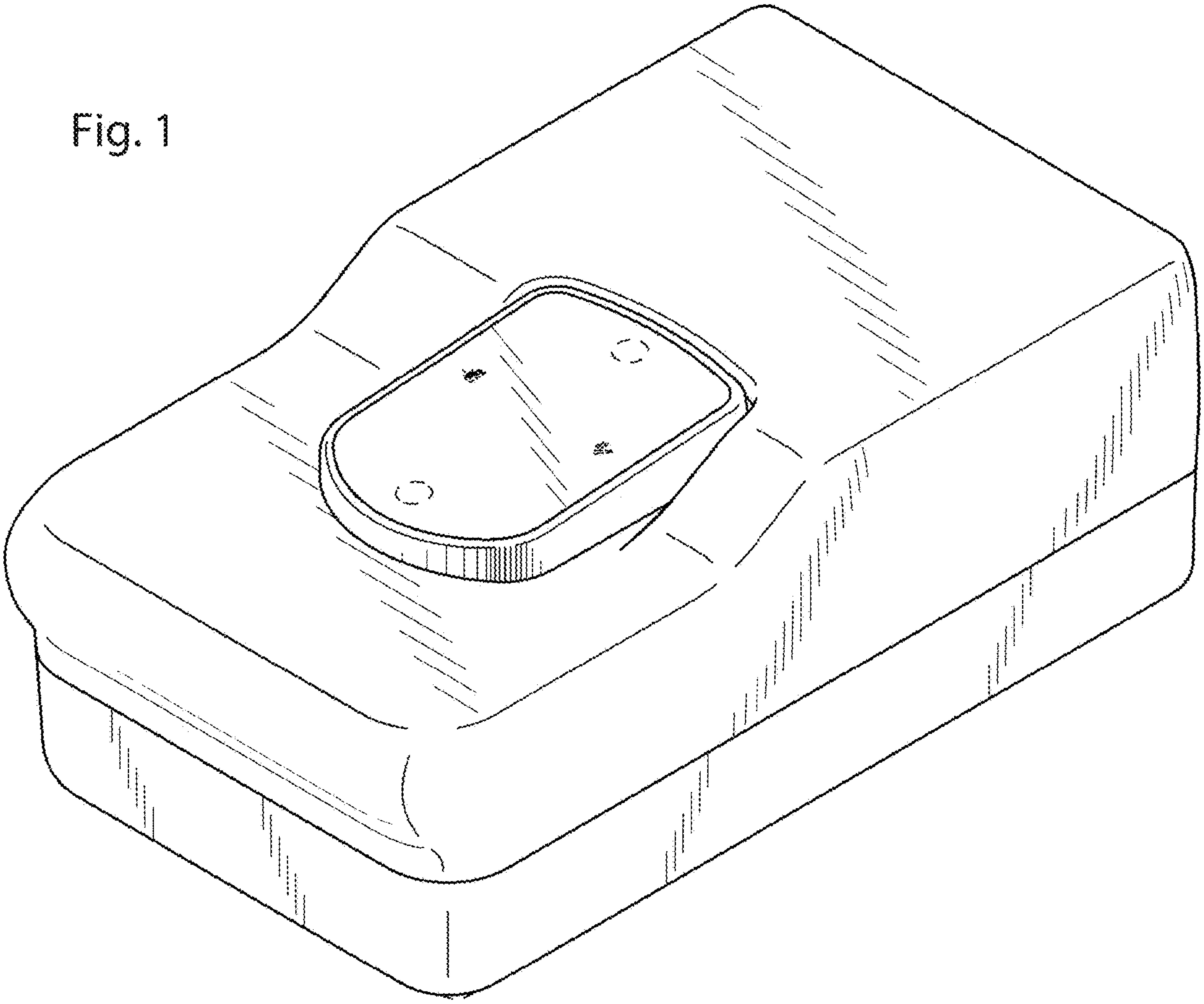


Fig. 2

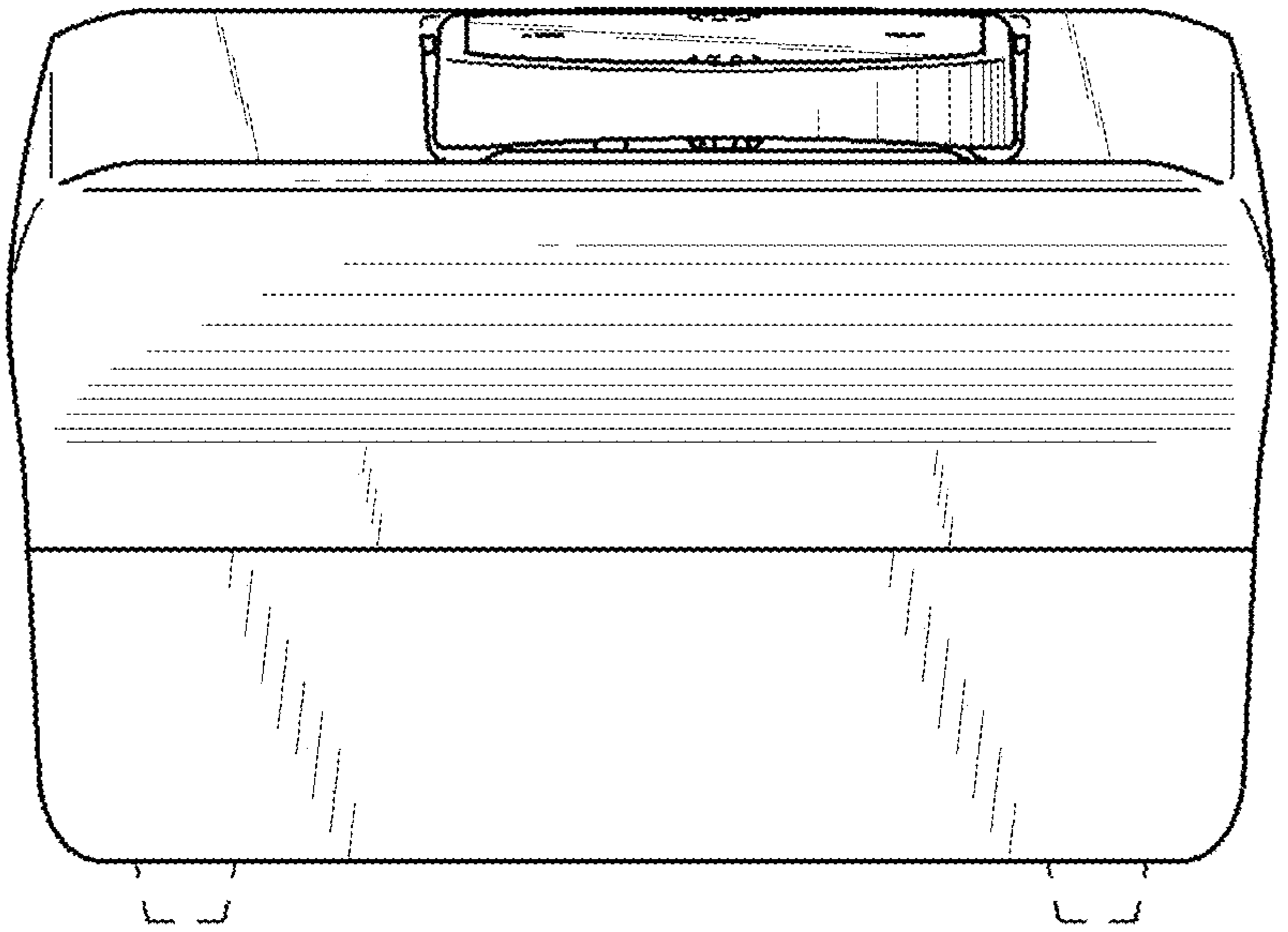
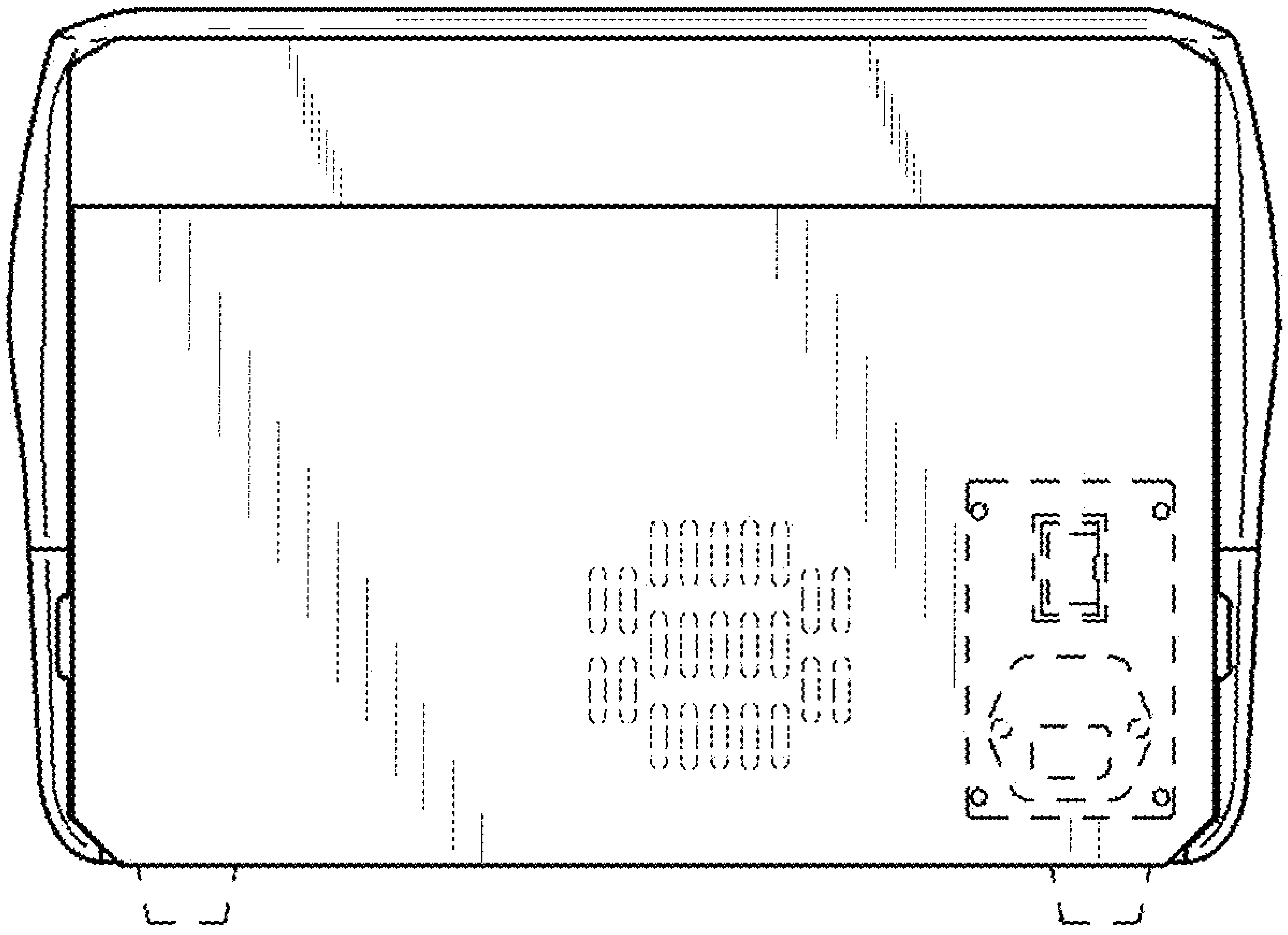


Fig. 3



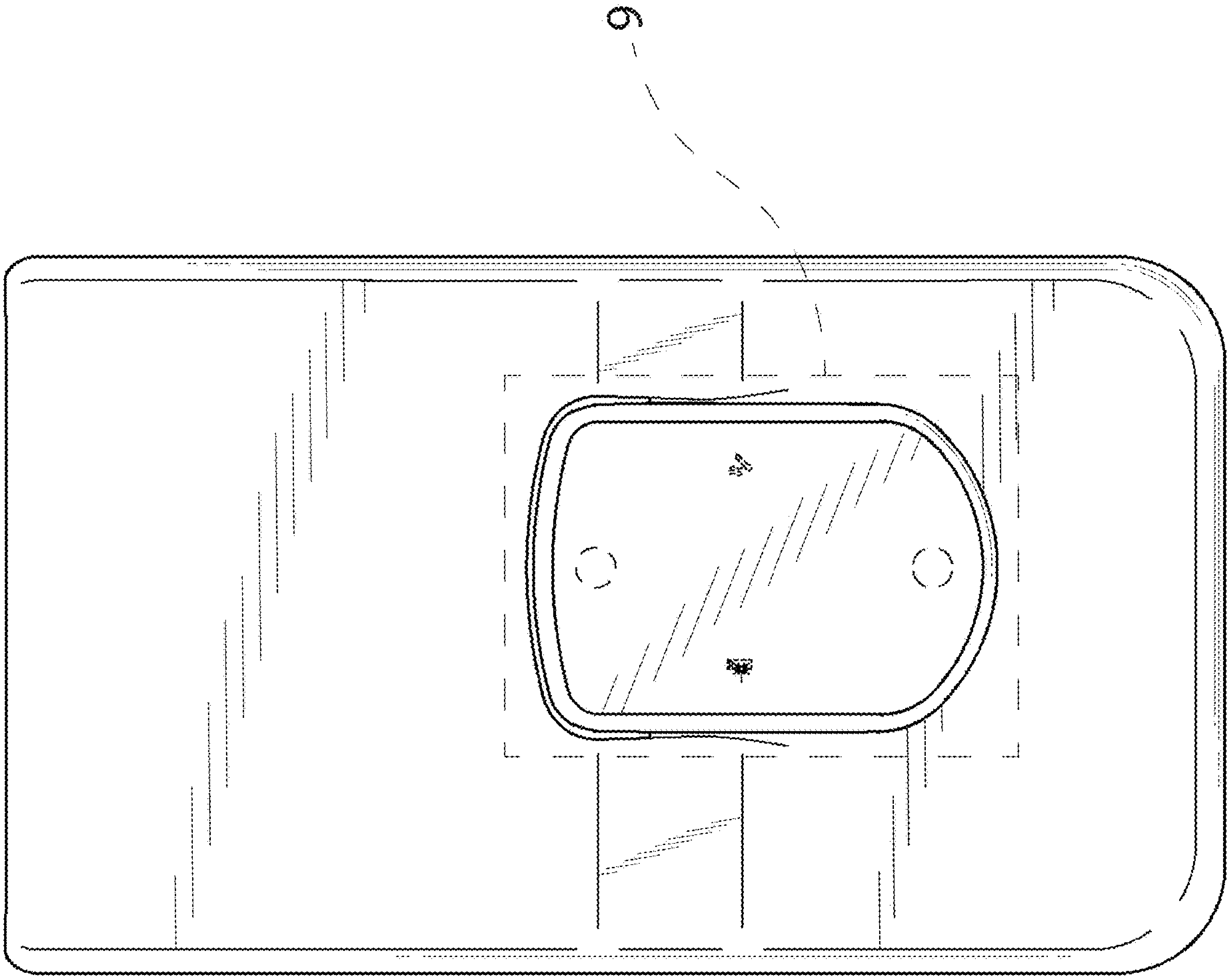


Fig. 4

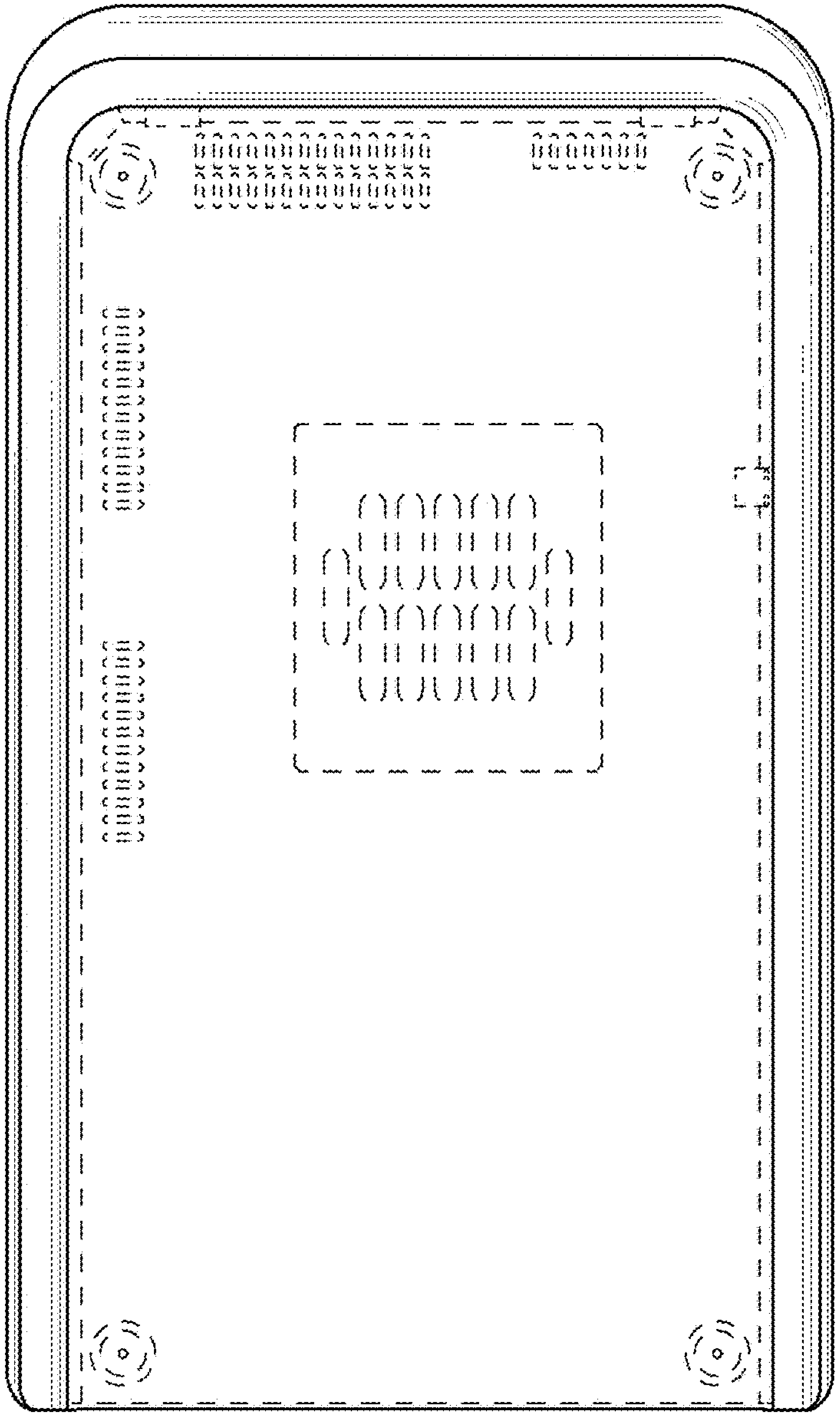


Fig. 5

Fig. 6

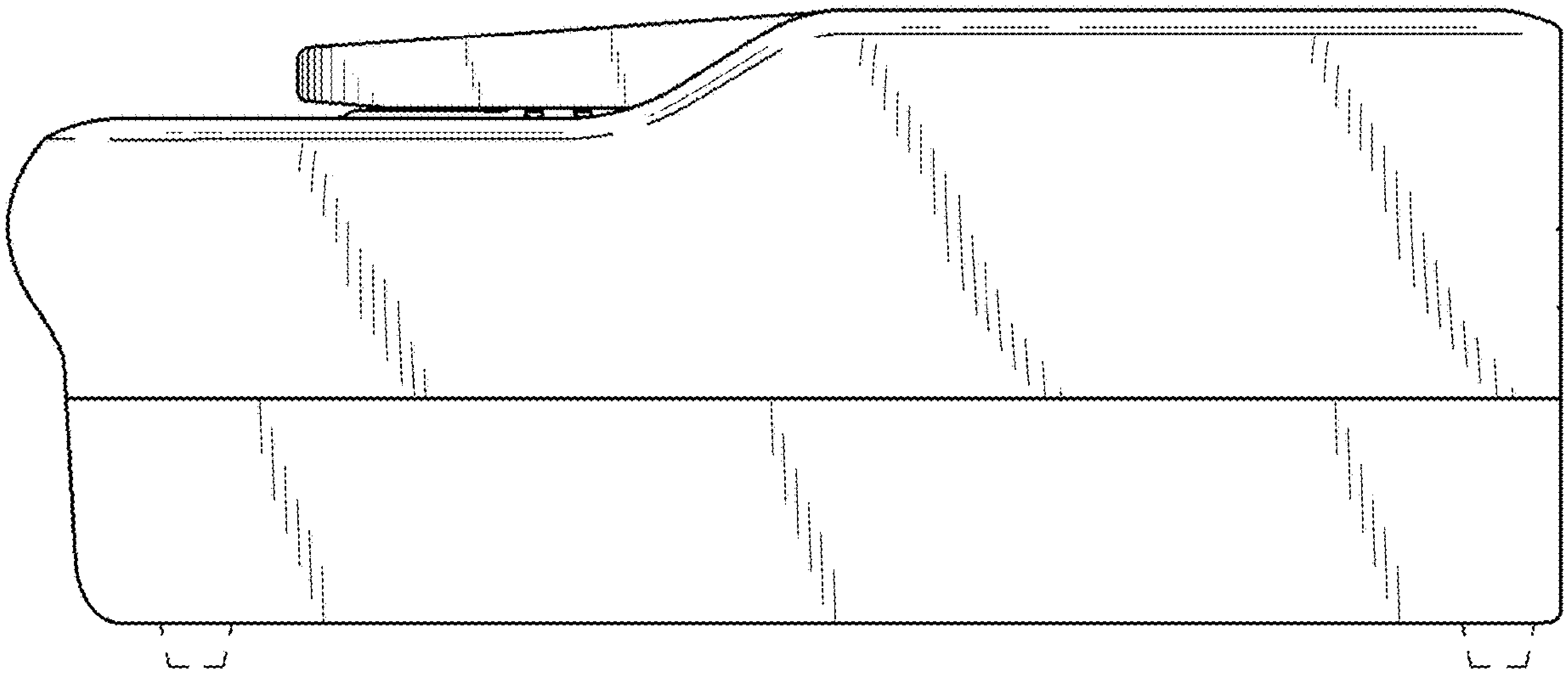


Fig. 7

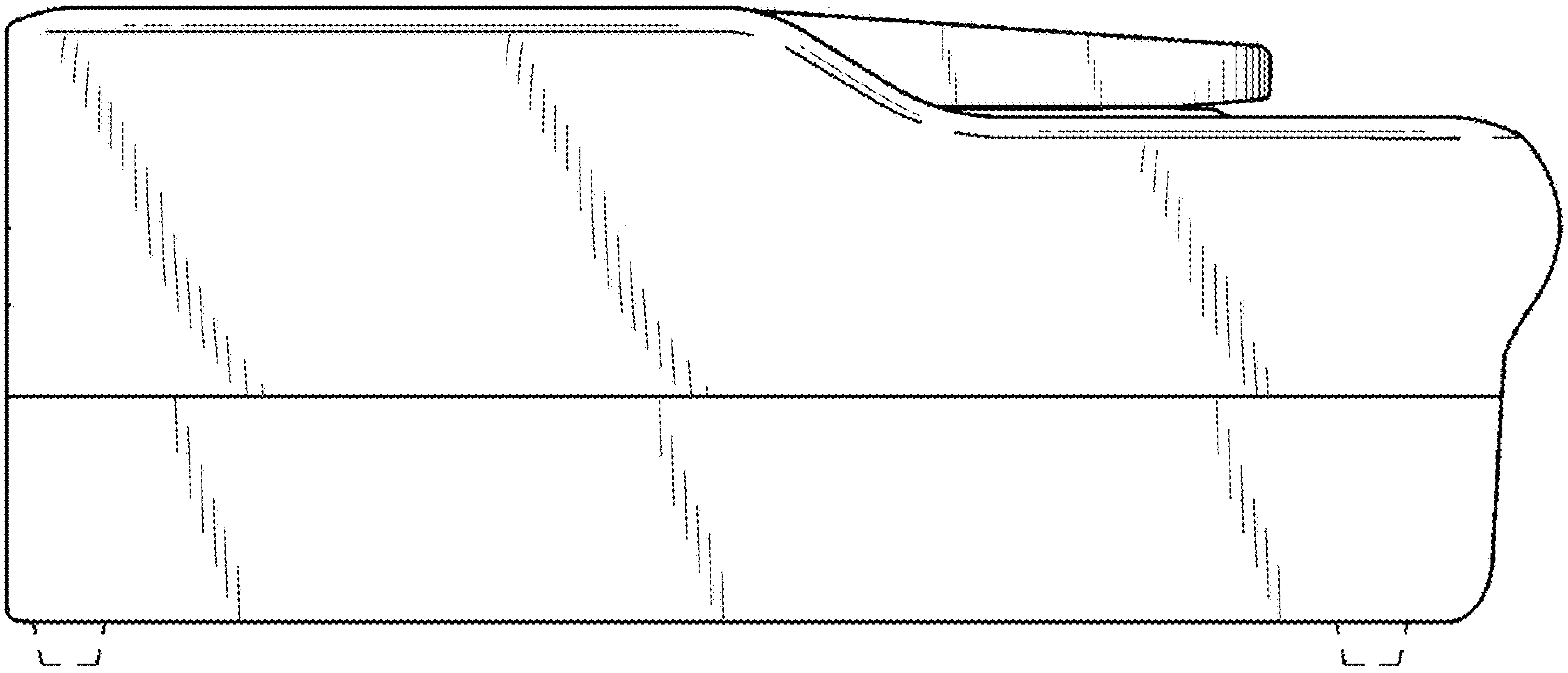
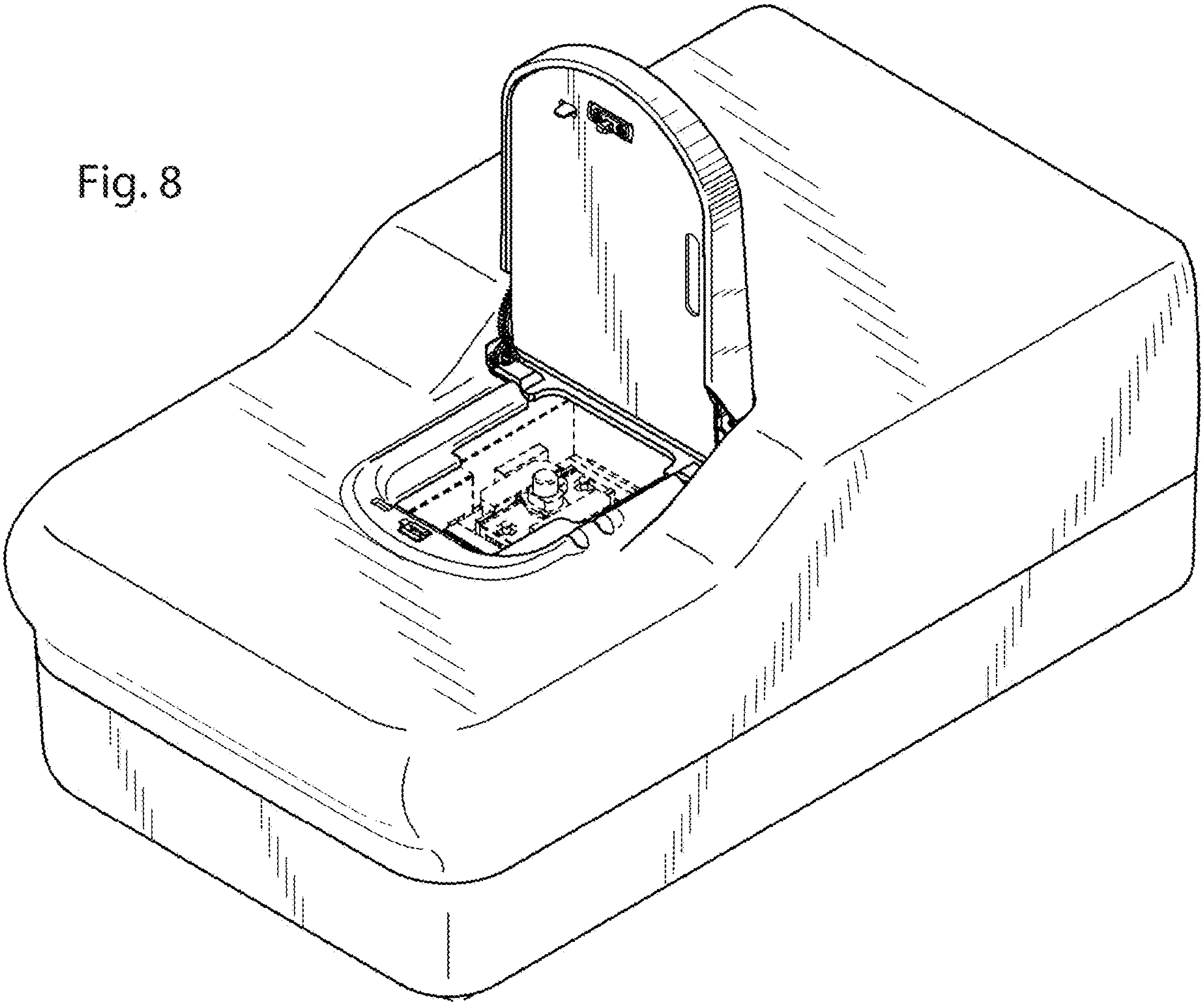


Fig. 8



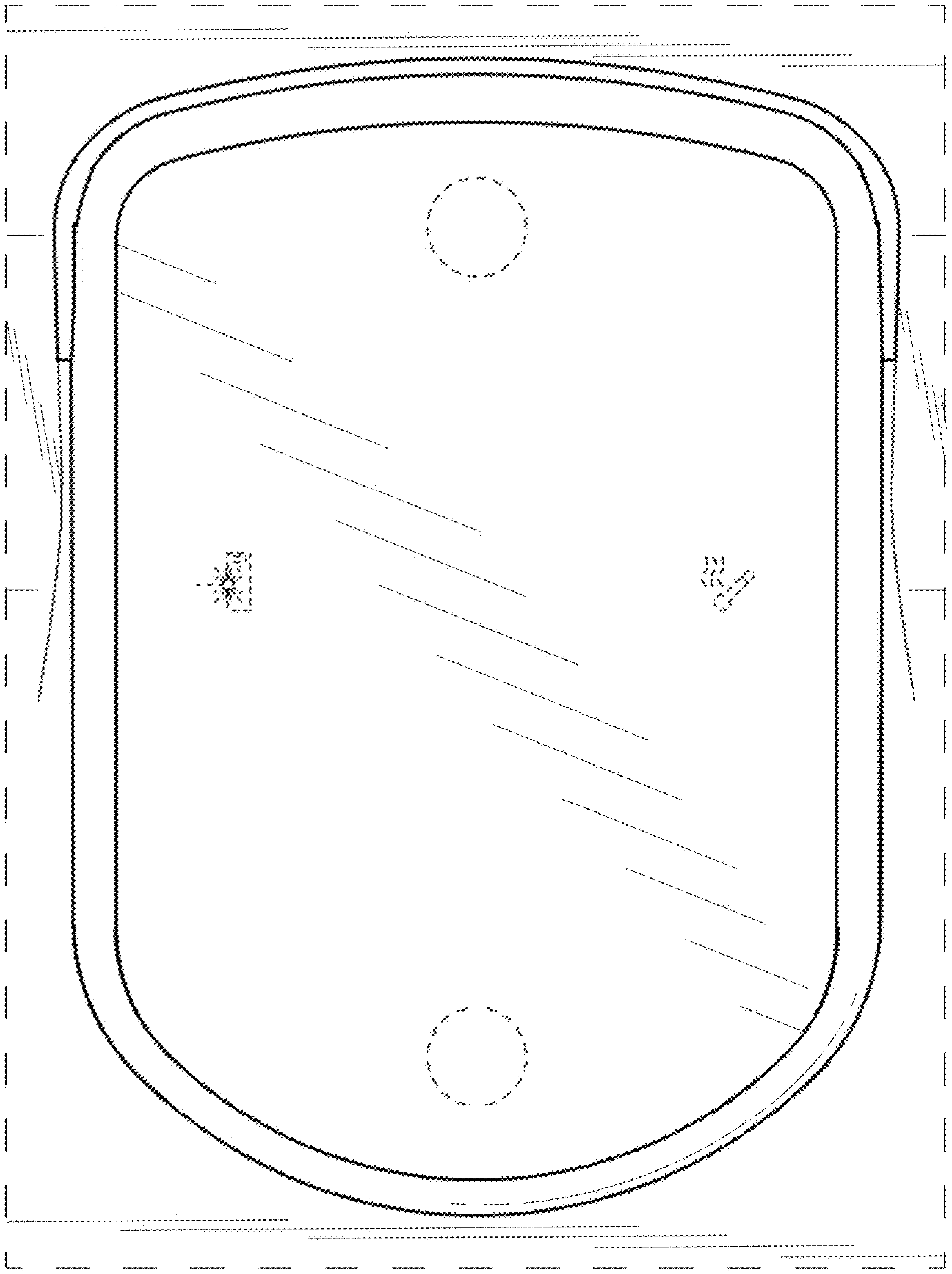


Fig. 9